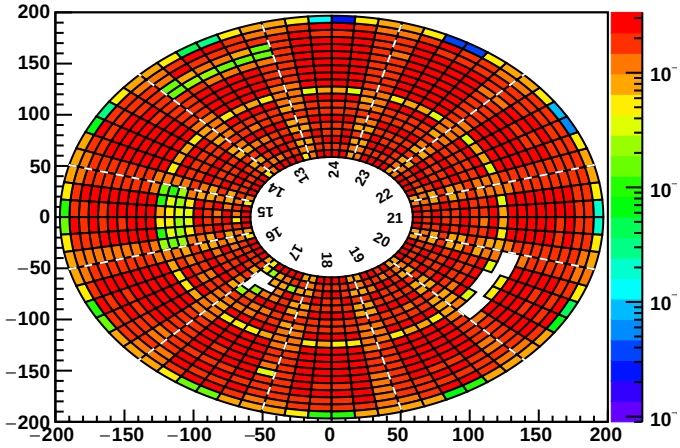
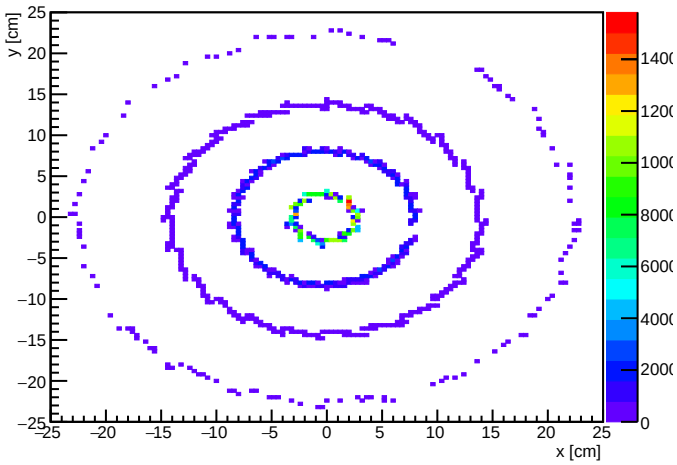
QA plots for pAu 200GeV run 2015 for 2025-05-01

General Hists

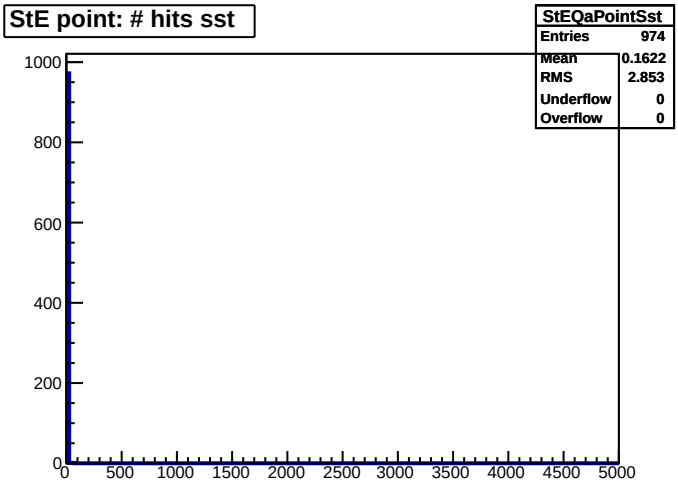
StE point: r-phi distribution of charge, tpcE



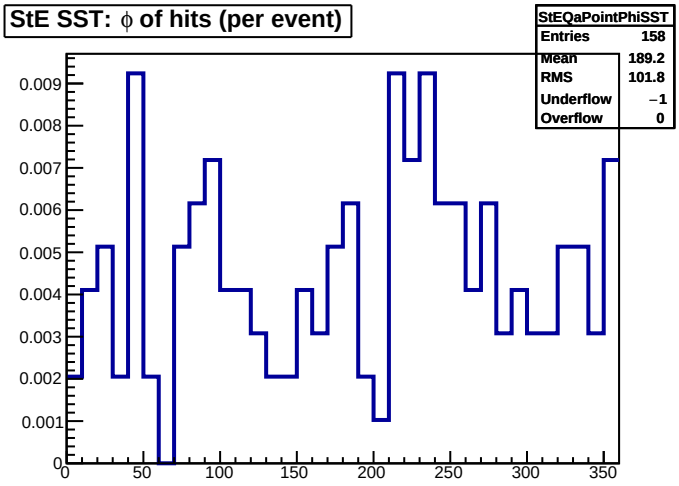
PIXEL, IST, SSD: Distribution of hits in XY



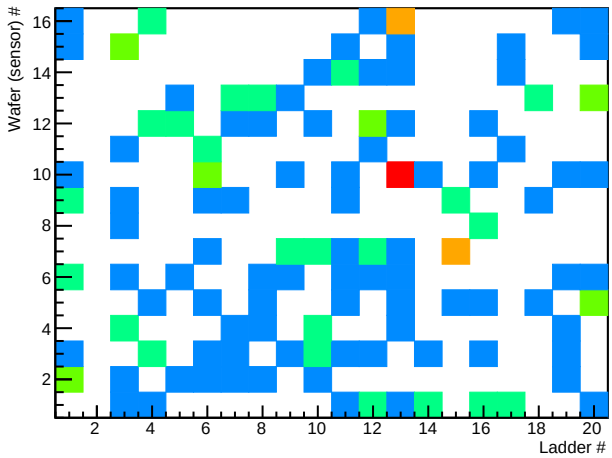
StE point: # hits sst



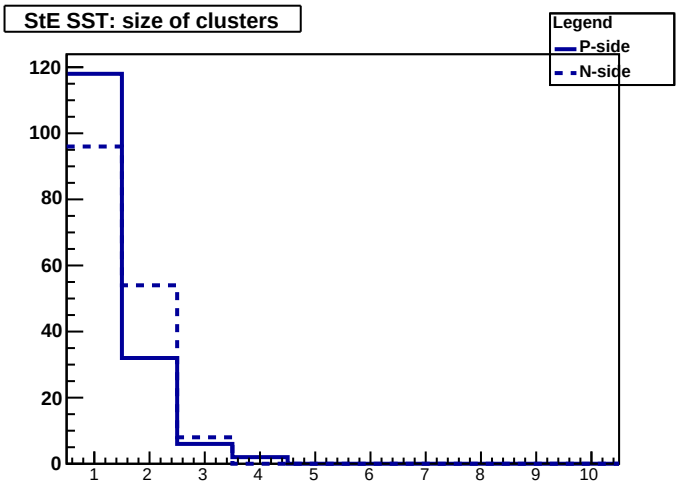
StE SST: ϕ of hits (per event)



StE SST: wafer id vs ladder id (per event)



StE SST: size of clusters



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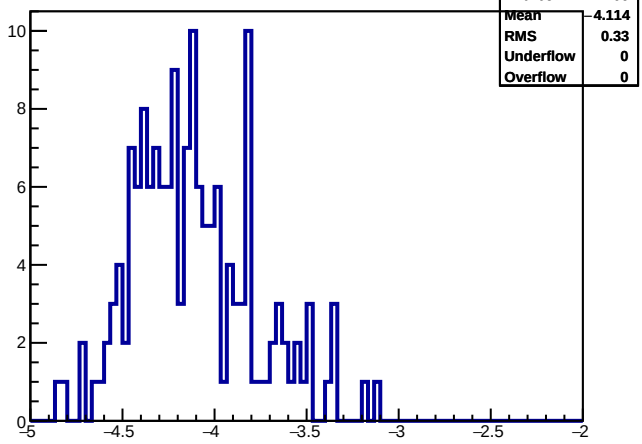
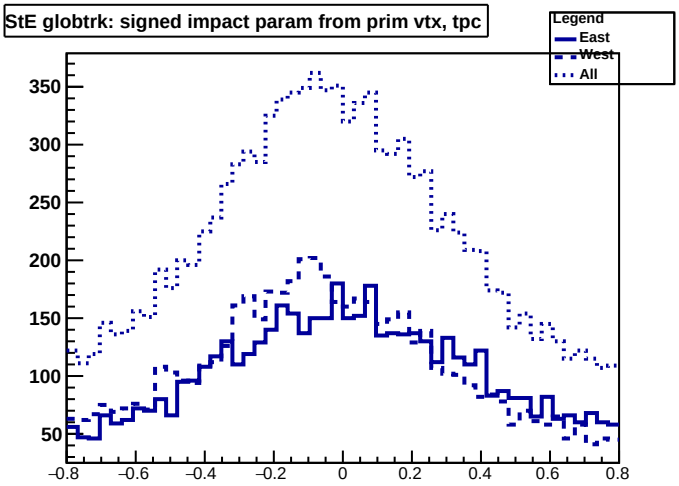
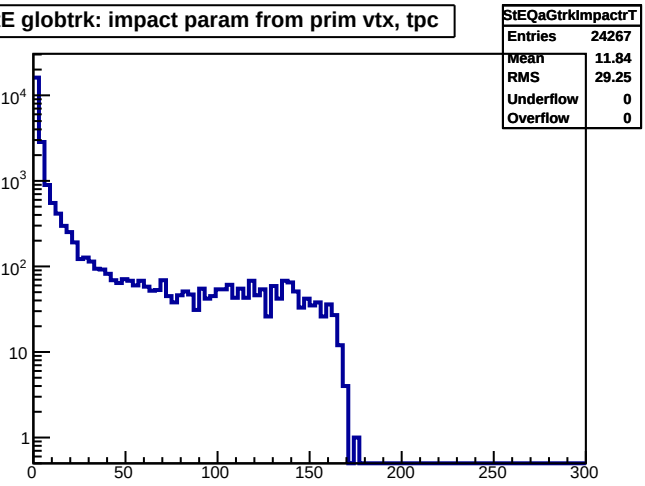
StE SST: log10(energy) of hits



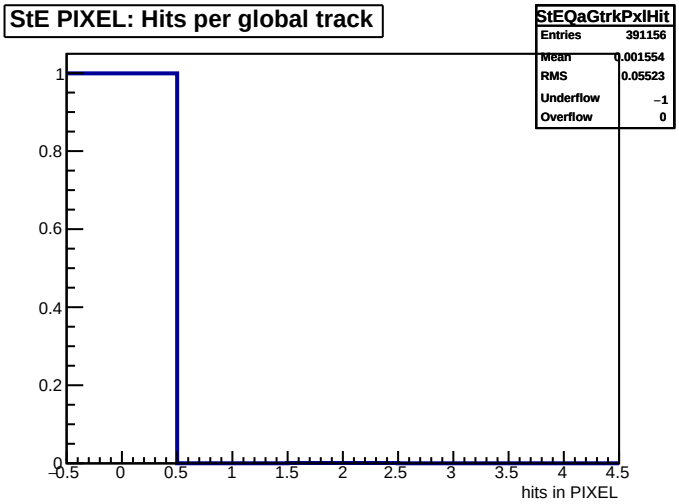
StE globtrk: signed impact param from prim vtx, tpc



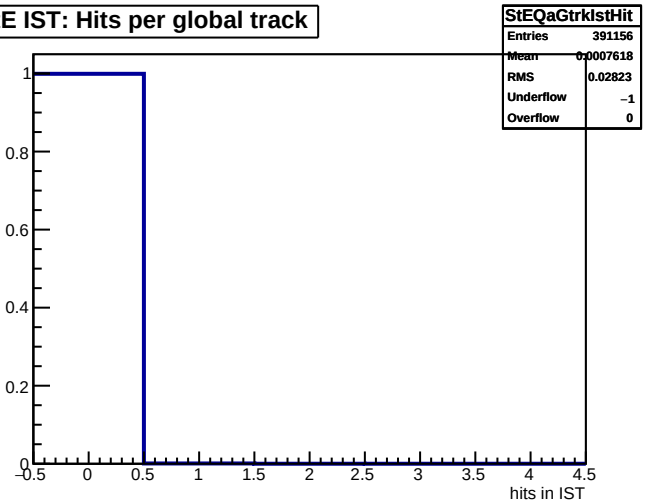
StE globtrk: impact param from prim vtx, tpc



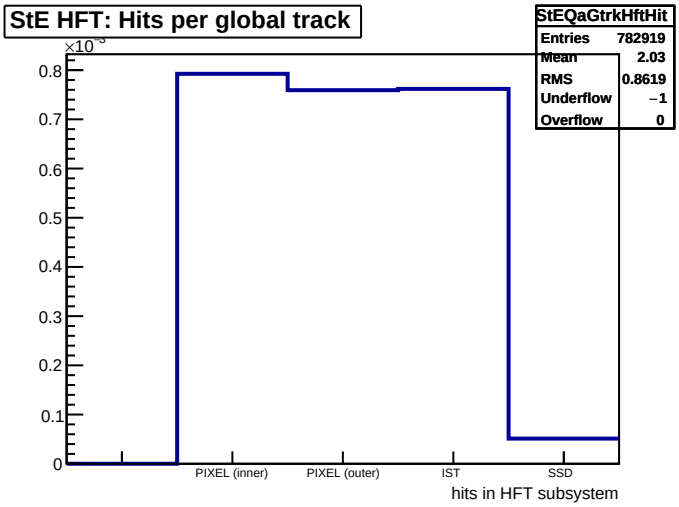
StE PIXEL: Hits per global track



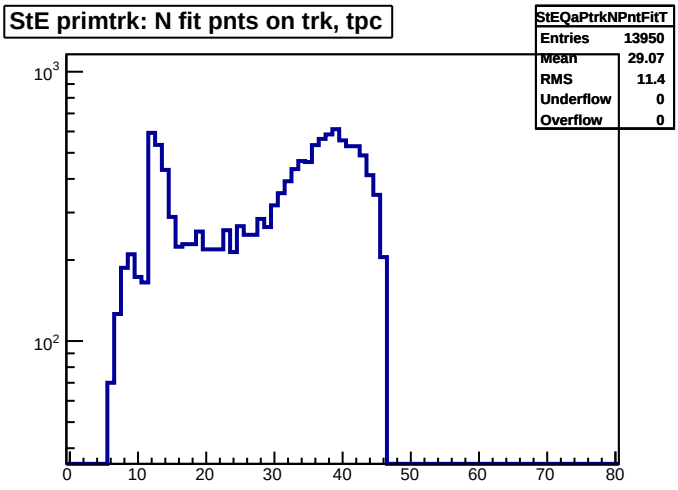
StE IST: Hits per global track



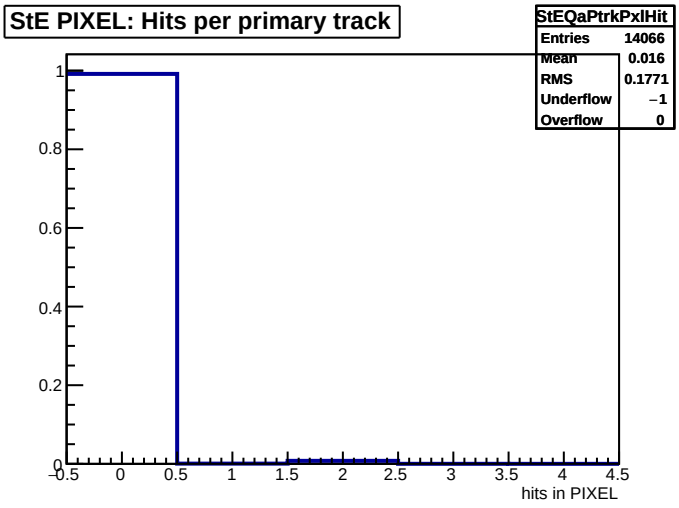
StE HFT: Hits per global track



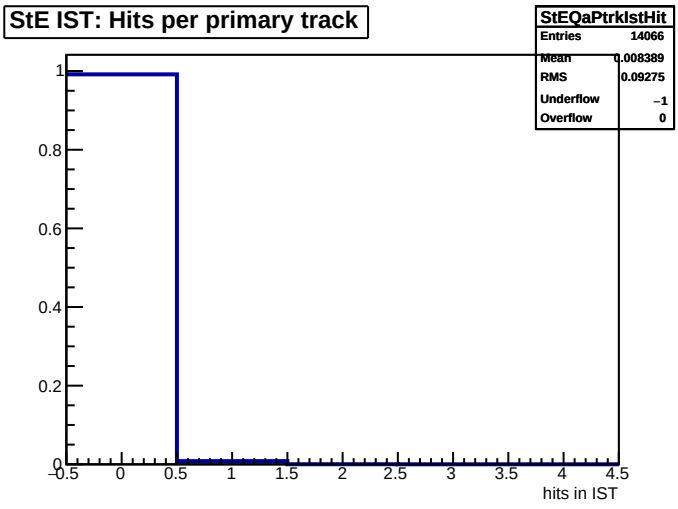
StE primtrk: N fit pnts on trk, tpc



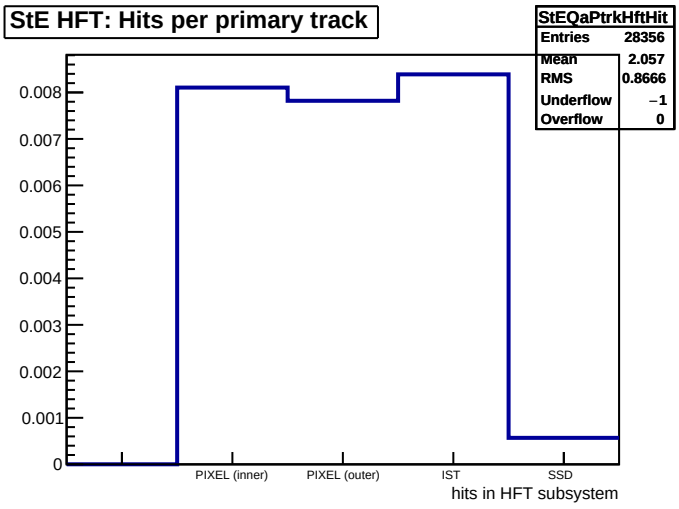
StE PIXEL: Hits per primary track



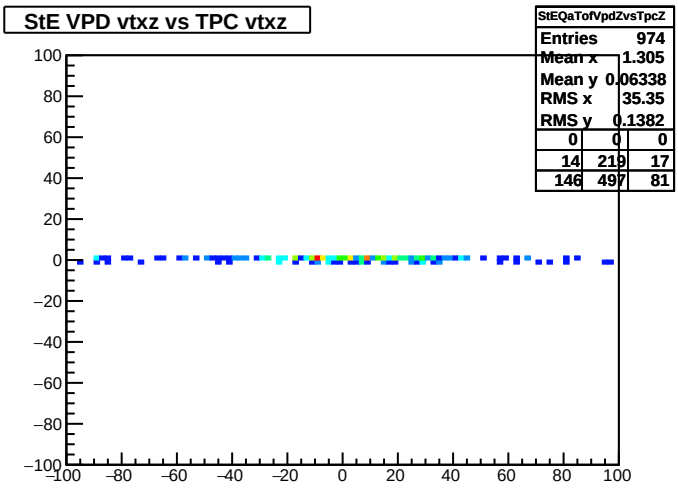
StE IST: Hits per primary track



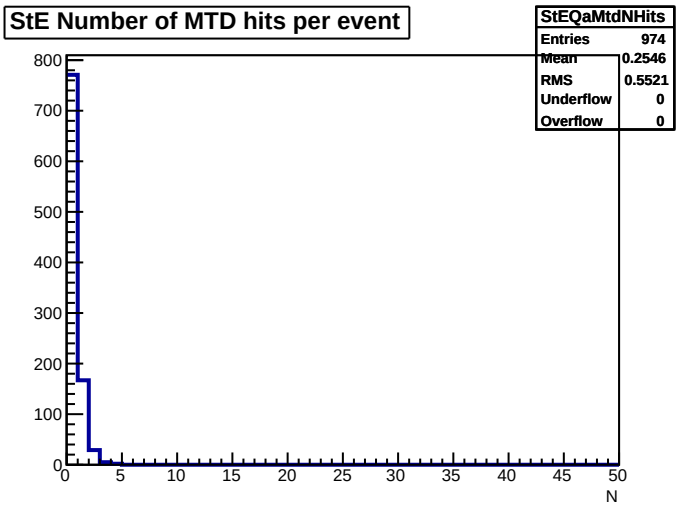
StE HFT: Hits per primary track



StE VPD vtxz vs TPC vtxz



StE Number of MTD hits per event



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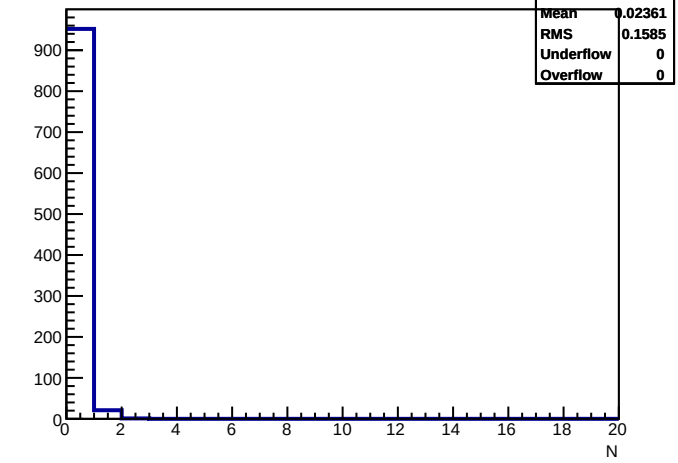
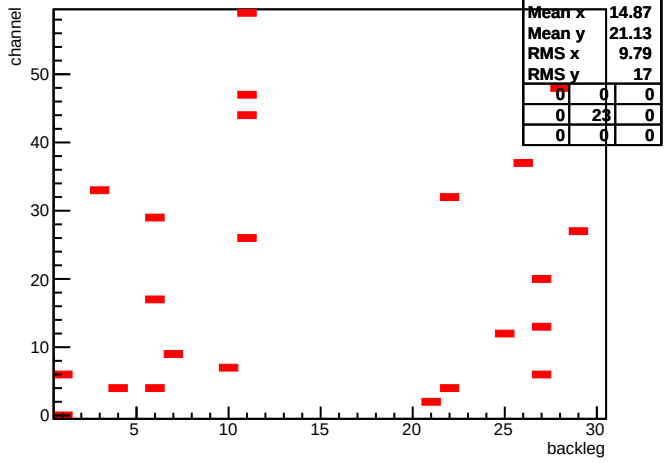
General Hists

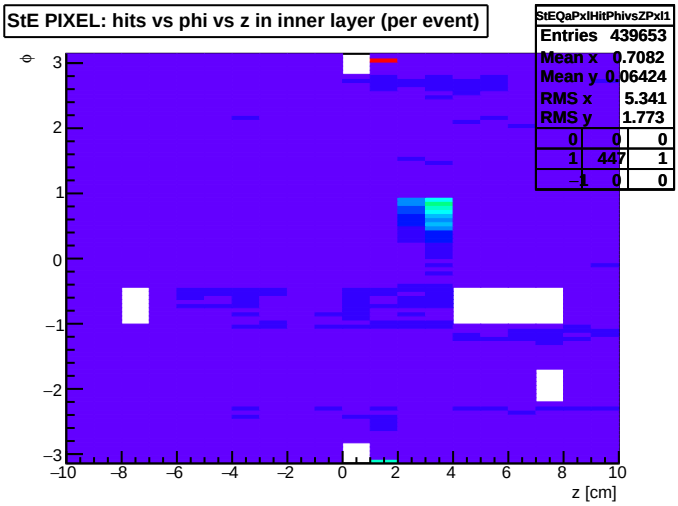
StE Number of matched MTD hits per event



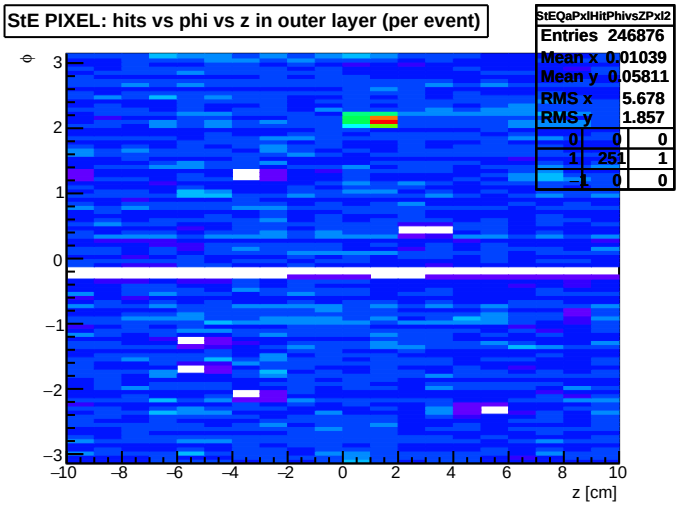
StE MTD: channel vs backleg of matched hits



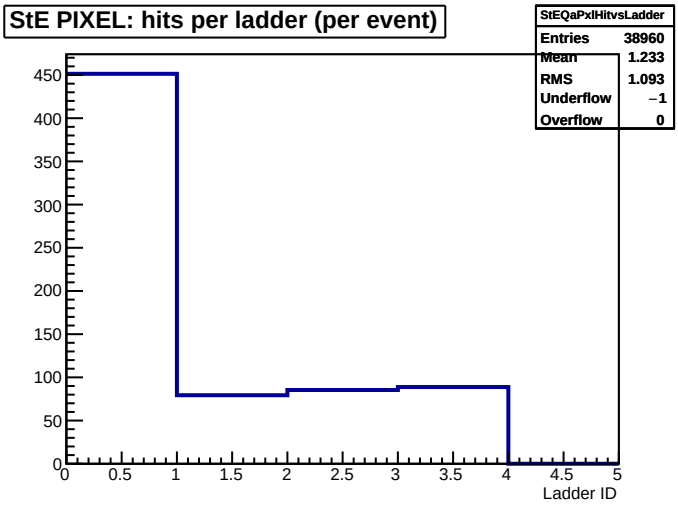
StE PIXEL: hits vs phi vs z in inner layer (per event)



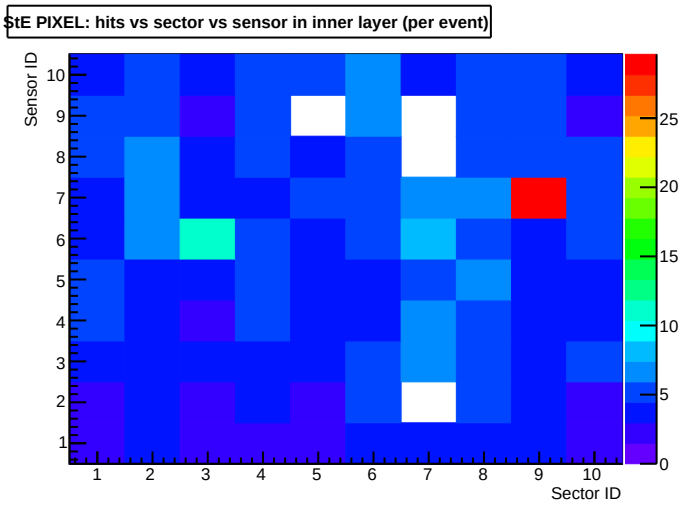
StE PIXEL: hits vs phi vs z in outer layer (per event)



StE PIXEL: hits per ladder (per event)



StE PIXEL: hits vs sector vs sensor in inner layer (per event)



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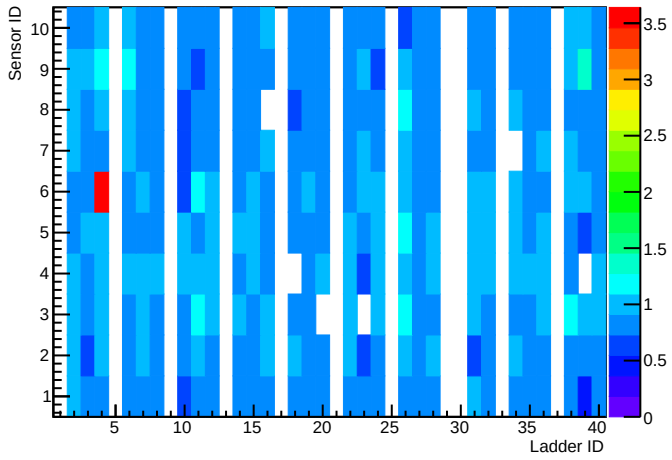
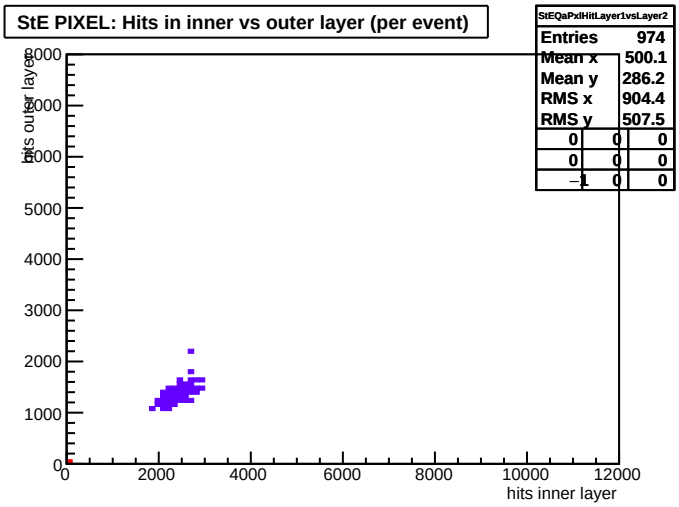
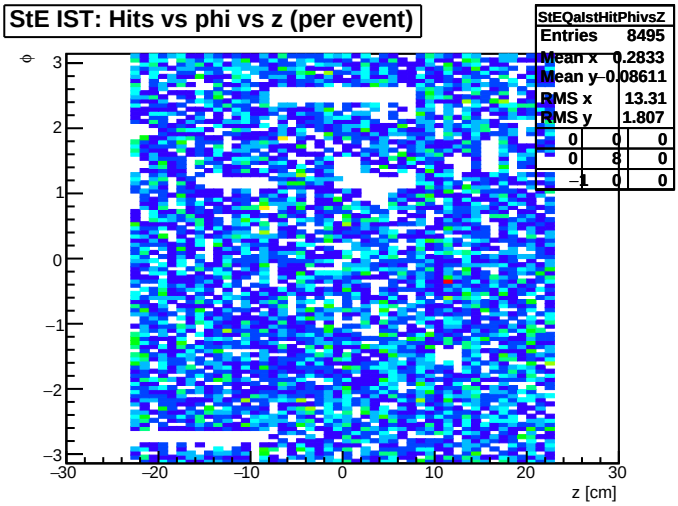
StE PIXEL: hits vs ladder vs sensor in outer layer (per event)



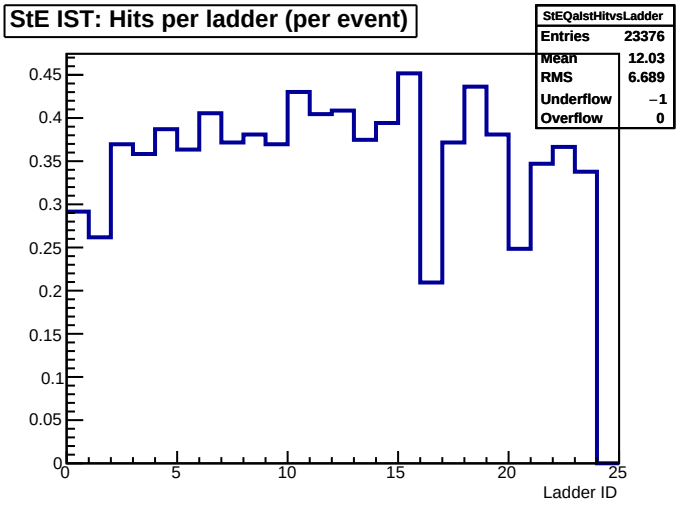
StE PIXEL: Hits in inner vs outer layer (per event)



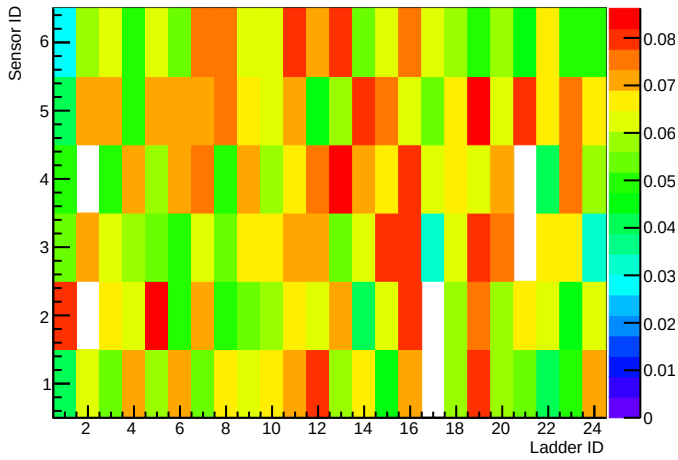
StE IST: Hits vs phi vs z (per event)



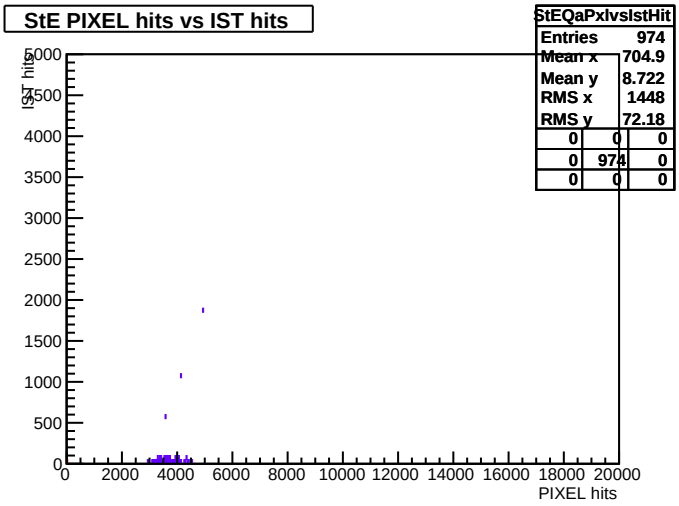
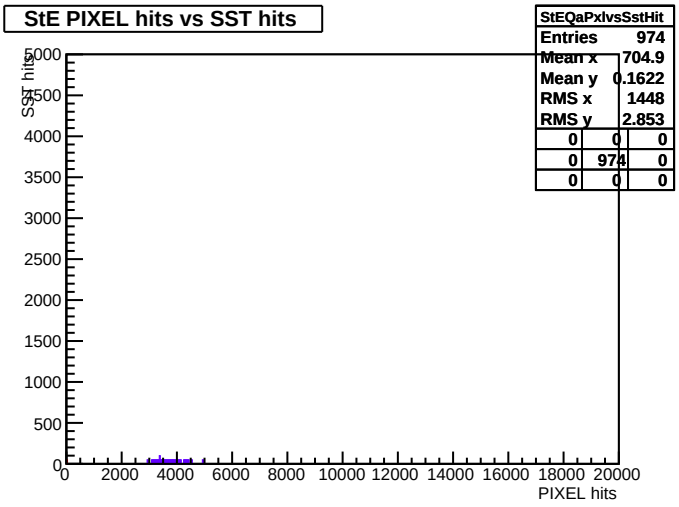
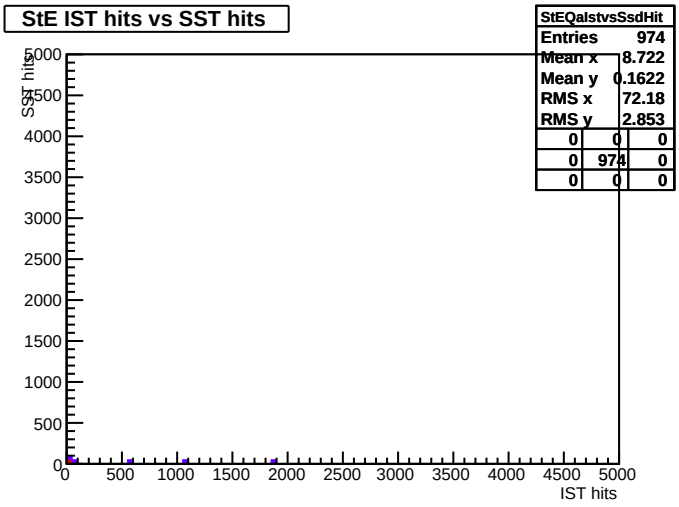
StE IST: Hits per ladder (per event)



StE IST: Hits vs ladder vs sensor (per event)



StE PIXEL hits vs IST hits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